

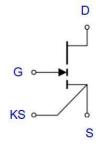
### Description

SGN65N400DF is an enhancement mode GaN-on-silicon transistor. GaN is a wide band gap semiconductor with high power density. The gallium nitride transistor is characterized by no body diode, so the reverse recovery charge is zero.

#### Features

- 650 V enhancement mode power switch
- R<sub>DS(on)</sub> =400mΩ
- I<sub>DS(max)</sub> = 7.5A
- Easy gate drive requirements (0 V to 6 V)
- Very high switching frequency (> 10 MHz)
- Fast and controllable fall and rise times
- Zero reverse recovery loss

#### **Device Information**



Part Number	Marking Code	Package	Packing
SGN65N400DF	SGN65N400	DFN5×6	4000pcs/reel
•			р  s

SGN65N400DF DFN5x6

SGN65N400DF Bottom View

G KS NC NC

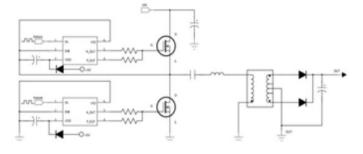


# SGN65N400DF

#### E-mode GaN-on-Silicon FET

# Applications

- Fast Battery Charging
- LED lighting drivers
- Power Factor Correction
- LLC Converters
- Wireless Power Transfer



Typical application circuit for LL

## Absolute Maximum Ratings (Tc=25 ℃ unless otherwise specified)

Parameter	Symbol	Value	Unit	Condition
Drain-Source voltage	V <sub>DS</sub>	650	V	
Gate-source voltage	$V_{GS}$	-7 to 6	V	
• · · · · · · · · · · ·	Ι <sub>D</sub>	7.5	А	Tc=25℃
Continuous drain current*		5	А	<b>Tc=100</b> ℃
Operation and storage	Tj	-55 to 150	°C	
temperature	Tstg	-55 to 150	°C	

\* An Estimated Value



## **Thermal characteristics**

Parameter	Symbol	Values	Unit	Note/Test Condition
Thermal resistance, junction-ambient	RthJA	37.1	°C/W	
Thermal resistance, junction-case	RthJC	1.9	°C/W	
Maximum reflow soldering temperature	Tsold	260	°C	MSL3

# Electrical Characteristics (Tc=25 $^\circ C$ unless otherwise specified)

Typical Performance – Static

Demonster	Grande al	Values			11	<b>T</b>	
Parameter	Symbol	Min.	Туре.	Max.	Unit	Test condition	
Drain source breakdown voltage	BVDS	650	/	/	V	VGS=0V, ID=20μΑ	
Total drain	Inco	/	0.3	10	μA	VDS=650V, VGS=0V, Tj=25℃	
leakage current	IDSS	/	5	75	μΑ	VDS=650V, VGS=0V, Tj=150℃	
Gate-to-source current	IGSS	/	2	/	μΑ	VDS=0V, VGS=6V, Tj=25℃	
Static drain-source RDS( on-resistance	RDS(ON)	/	350	400	mΩ	VGS=6V, ID=3A, Tj=25℃	
		/	650	/	mΩ	VGS=6V, ID=3A, Tj=150℃	
Gate threshold voltage	VGS(th)	1.2	1.6	2.0	V	VDS=VGS, ID=3.5mA,	



E-mode GaN-on-Silicon FET

# **Typical Performance – Dynamic**

_		Values			_	
Parameter	Symbol	Min	Туре	Max	Unit	Test condition
Input capacitance	C <sub>ISS</sub>	/	32	/	pF	N 400V
Output capacitance	C <sub>oss</sub>	/	9	/	pF	V <sub>DS</sub> =400V, V <sub>GS</sub> =0V,
Reverse transfer Capacitance	C <sub>RSS</sub>	/	0.3	/	pF	f=1MHz
Output capacitance, energy Related	C <sub>OSS(er)</sub>	/	15	/	рF	V <sub>DS</sub> =0V to
Output capacitance time related	C <sub>OSS(tr)</sub>	/	21	/	рF	400V,V <sub>GS</sub> =0V
Total gate charge	Q <sub>G</sub>	/	1.3	/	nC	
Gate-drain charge	$Q_{GD}$	/	0.33	/	nC	V <sub>DS</sub> =400V, V <sub>GS</sub> =0V to 6V
Gate-source charge	Q <sub>GS</sub>	/	0.6	/	nC	
Gate Resistance	R <sub>G</sub>	/	2.88	/	Ω	<i>f = f</i> res, Open drain



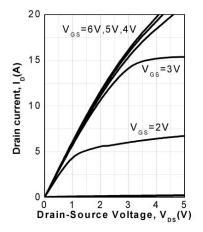


Fig.1 Typical output characteristics @ Tj=25  $^\circ\!\mathrm{C}$ 

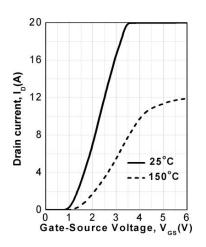


Fig.3 Typical transfer characteristics @ VDS=5V

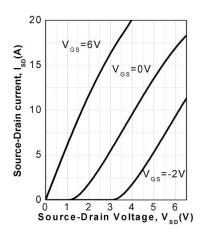


Fig.5 Typical reverse conduction characteristics

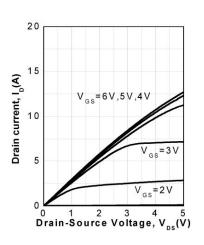


Fig.2 Typical output characteristics @ Tj=150  $^\circ C$ 

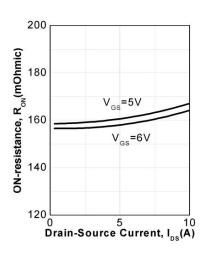


Fig.4 ON-resistance for various drain current @ 25  $^\circ\!\mathrm{C}$ 

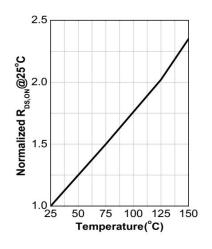


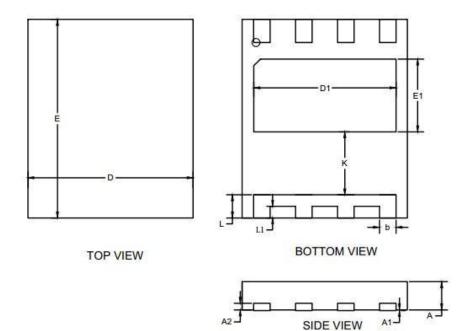
Fig.6 Normalized ON-resistance at various temperatures



E-mode GaN-on-Silicon FET

## Package

Dimensions(mm)						
Symbol	Min.	Nom.	Max.			
А	0.8	0.85	0.9			
A1	-	0.02	0.05			
A2		0.2(REF)				
b	0.45	0.50	0.55			
D	4.90	5.00	5.10			
D1	4.20	4.30	4.40			
E	5.90	6.00	6.10			
E1	2.10	2.20	2.30			
е	1.27					
k	1.9	-	-			
L	0.65	0.7	0.75			





#### Disclaimer

The content specified herein is for the purpose of introducing SET's products (hereinafter "Products"). The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. Examples of application circuits, circuit constants and any other information contained herein illustrate the standard usage and operations of the Products. The peripheral conditions must be taken into account when designing circuits for mass production.

SET does not assume any liability for infringement of patents, copyrights, or other intellectual property rights of third parties by or arising from the use of the Products or technical information described in this document.

The Products are not designed or manufactured to be used with any equipment, device or system which requires an extremely high level of reliability the failure or malfunction of which may result in a direct threat to human life or create a risk of human injury (such as a medical instrument, transportation equipment, aerospace machinery, nuclear-reactor controller, fuel-controller or other safety device). SET shall bear no responsibility in any way for use of any of the Products for the above special purposes.

Although SET endeavors to improve the quality and reliability of its products, semiconductor products have specific characteristics such as the occurrence of failure at a certain rate and malfunctions under certain use conditions. Please be sure to implement safety measures to guard them against the possibility of physical injury, and injury or damage caused by fire in the event of the failure of a SET product.

The content specified herein is subject to change for improvement without notice. When using a SET product, be sure to obtain the latest specifications.